

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/532,213	FAHEY, MARK T
Examiner	Art Unit	
Jinhee J. Lee	2831	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
174	as above	7/27/2006	LEE
439	as above	/	/